

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/536,774 SHIRAFUJI ET AL.	
		Examiner	Art Unit KENISHA V. FORD	2812 Page 1 of 1

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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